

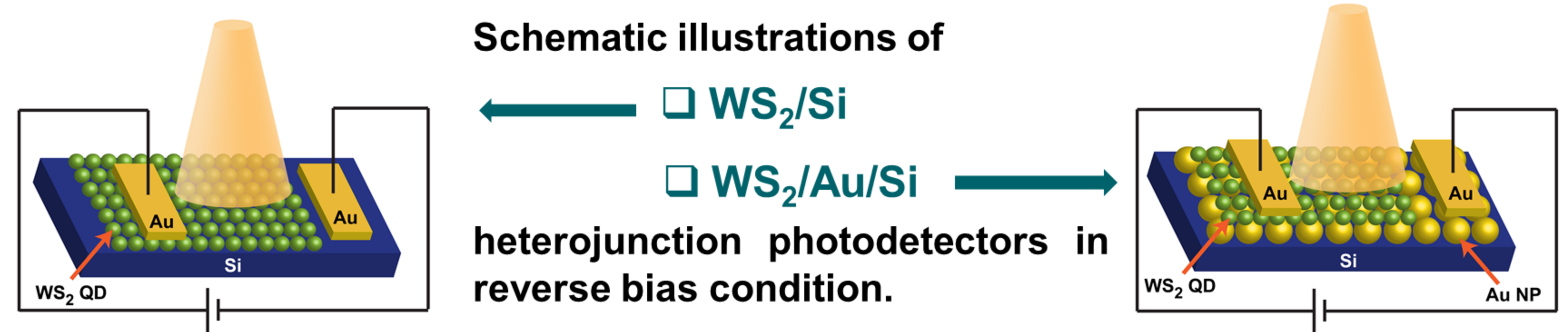
WS₂ quantum dot/Si heterojunction based self-biased photodetector with plasmon mediated suppressed dark current and fast photoresponse

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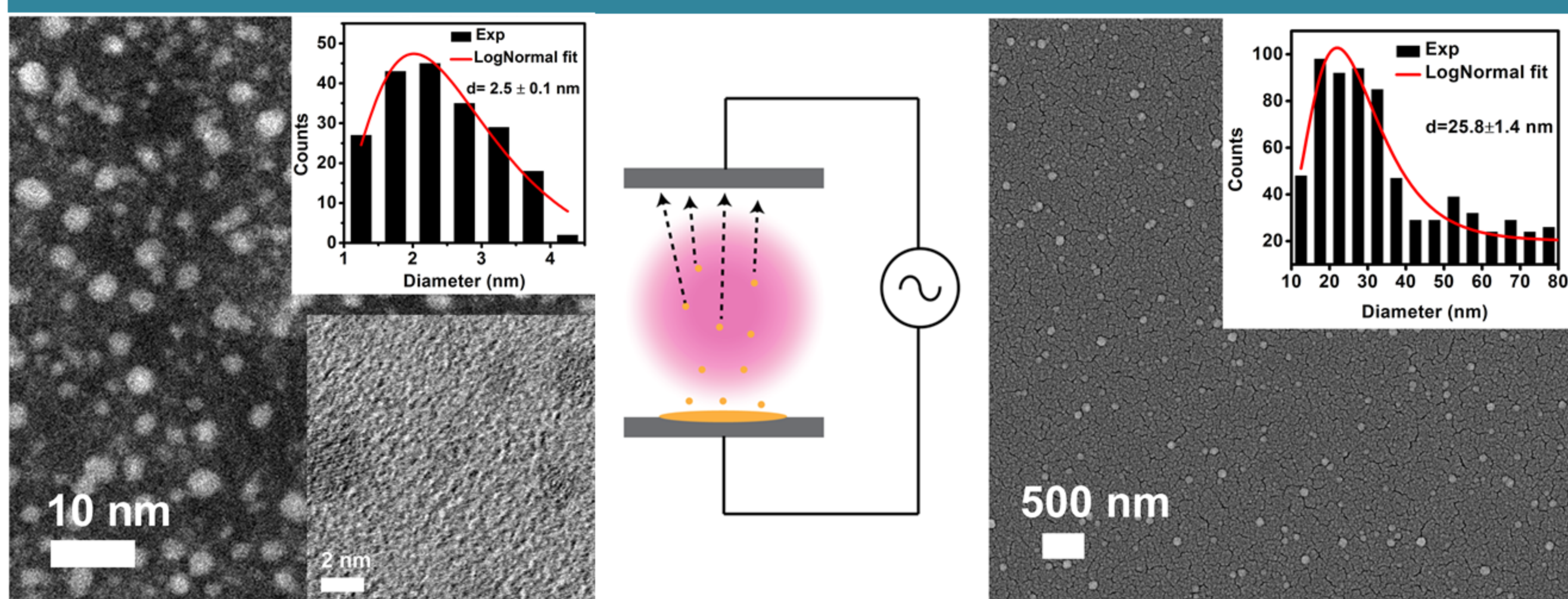
INTRODUCTION

- Van der Waals heterostructure based photodetectors built from WS₂ quantum dots (QDs) on a p-type Si platform.
- The WS₂ QD/Si photodetector (PD) can operate at zero bias owing to the separation of charge carriers by the built-in electric field.
- Integration of plasmonic Au nanoparticles (NPs) into the WS₂ QD/Si PD greatly improves the photodetector performance.

DEVICE FABRICATION

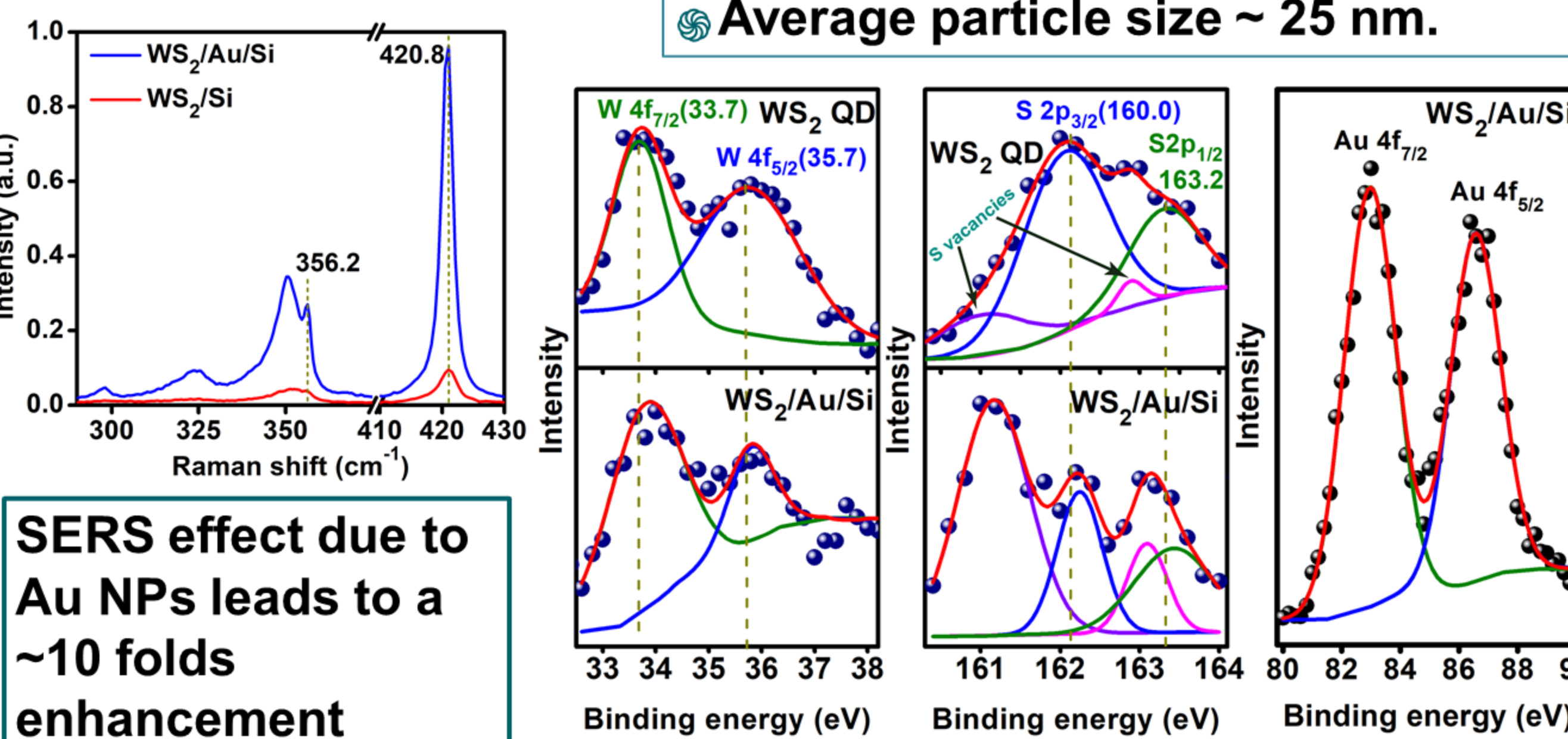


STRUCTURAL CHARACTERISTICS



HAADF and HR-TEM:
QDs of average size 2.5 nm. Lattice d-spacing of 2.3 Å.

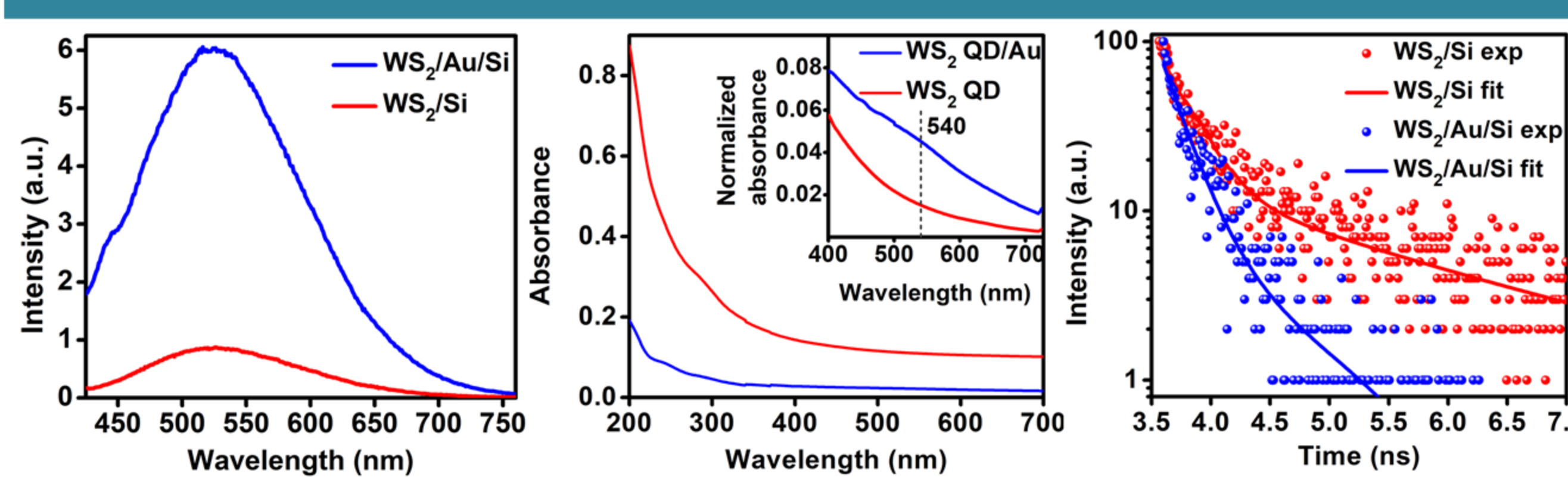
FESEM of Au NPs
 Au film deposition done by RF sputtering at -12V. Rapid thermal annealing done at 600 °C for 3 min.
 Average particle size ~ 25 nm.



SERS effect due to Au NPs leads to a ~10 folds enhancement

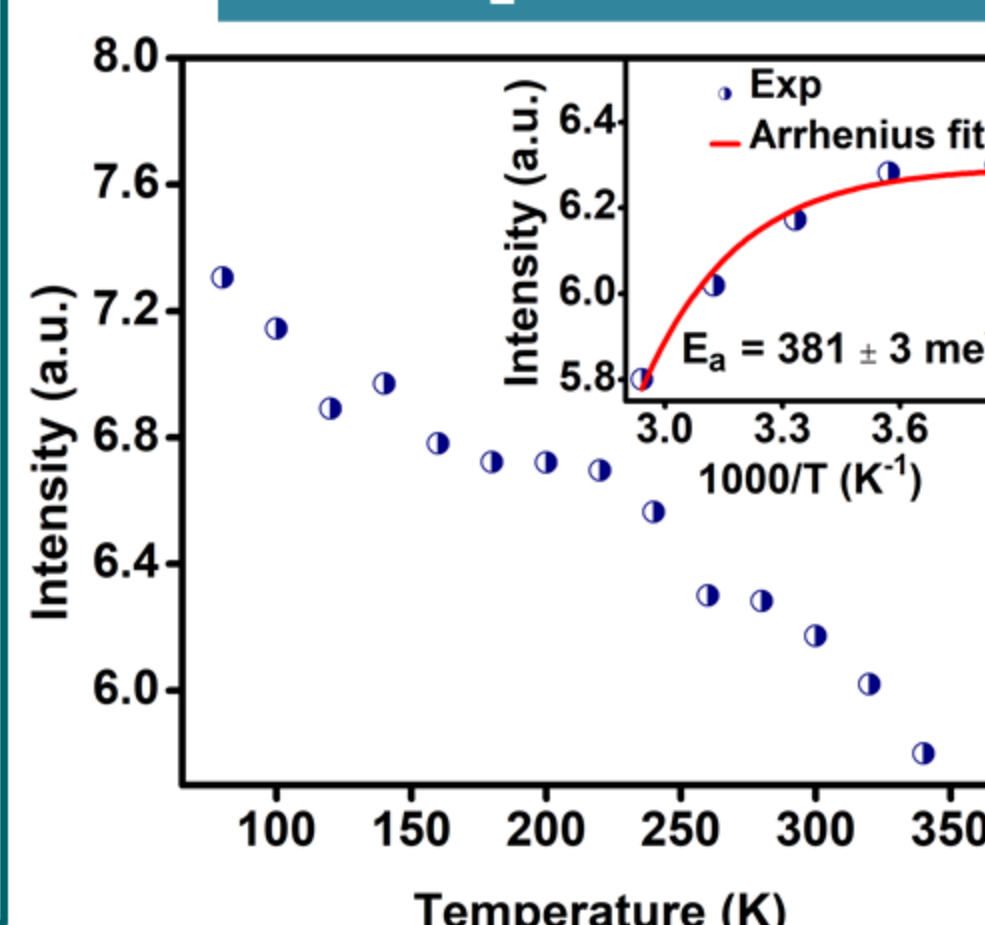
- The overall upshift of the binding energies of W and S indicates charge transfer or n type doping by Au NPs.
- The high resolution XPS peaks at 83.0 eV and 86.6 eV confirm the presence of elemental Au NPs.

OPTICAL CHARACTERISTICS

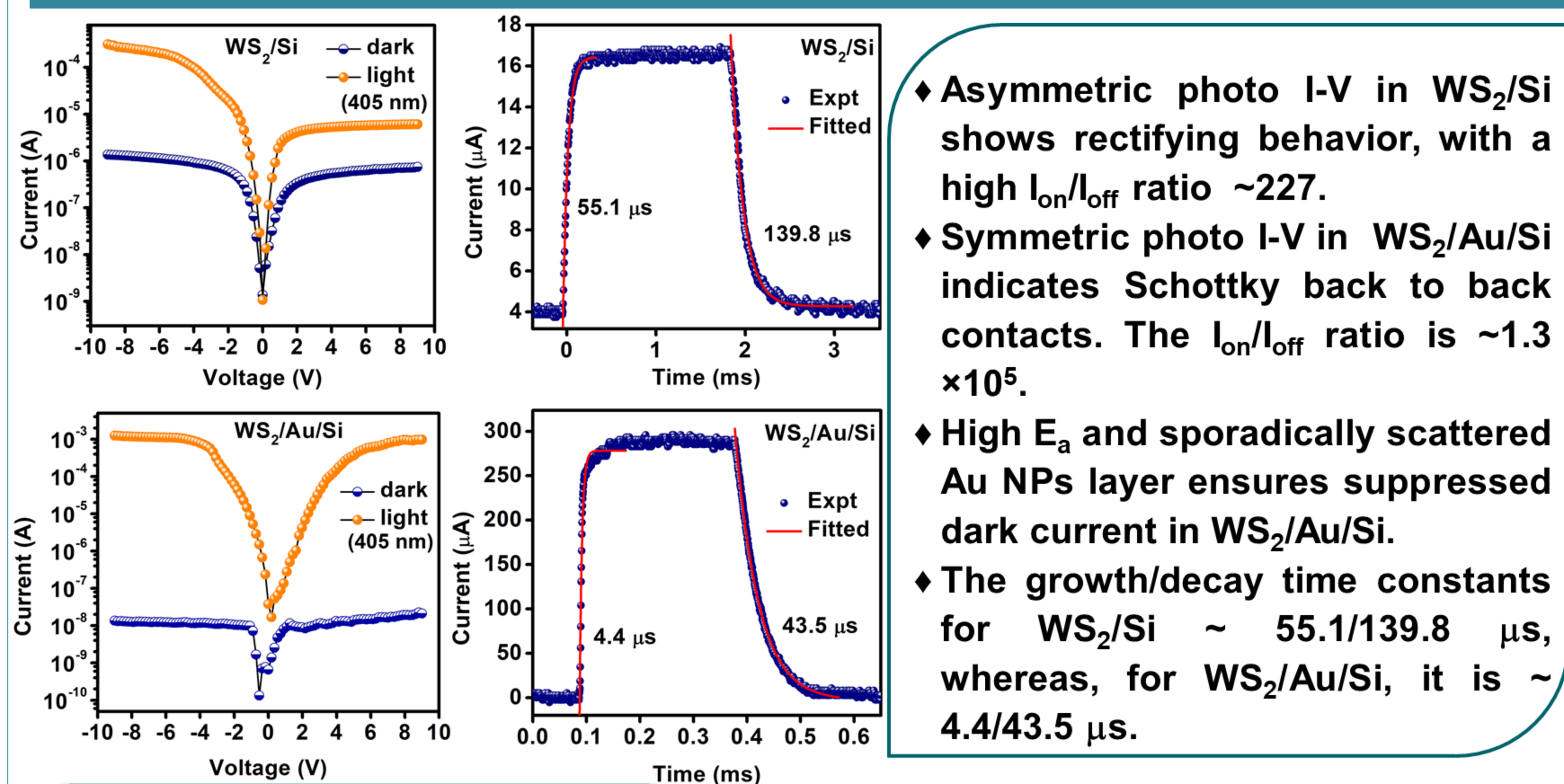


- There is ~6 fold PL enhancement of WS₂ QDs by Au NPs.
- The absorption hump at ~540 nm for WS₂/Au is induced by the creation and enhancement of the localized EM field or LSPR.
- Faster decay in WS₂/Au/Si due to high non-radiative decay rate from electron-plasmon interaction.
- High thermal activation energy (E_a) ~381 meV, thus, lesser the probability of thermal dissociation of excitons.

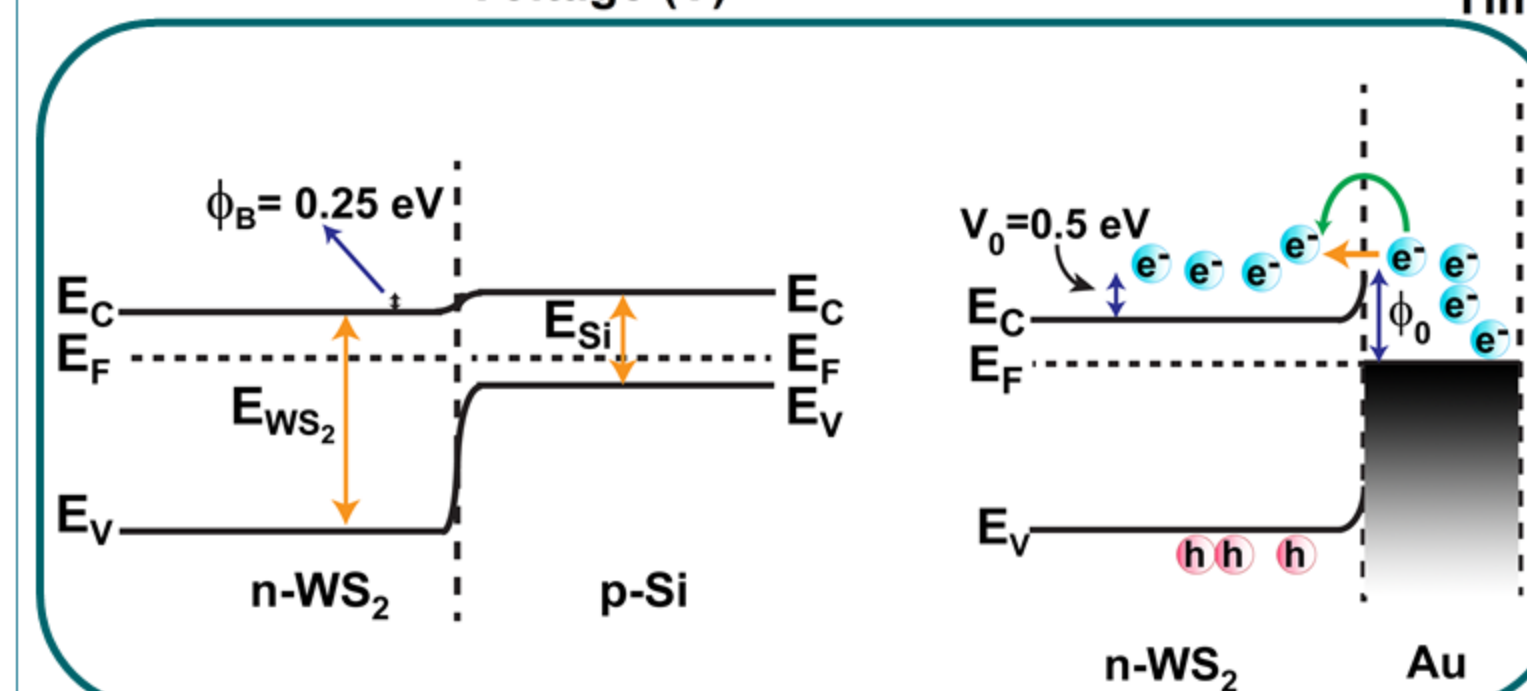
Temperature dependent PL of WS₂/Au/Si HS



PHOTODETECTOR PERFORMANCE

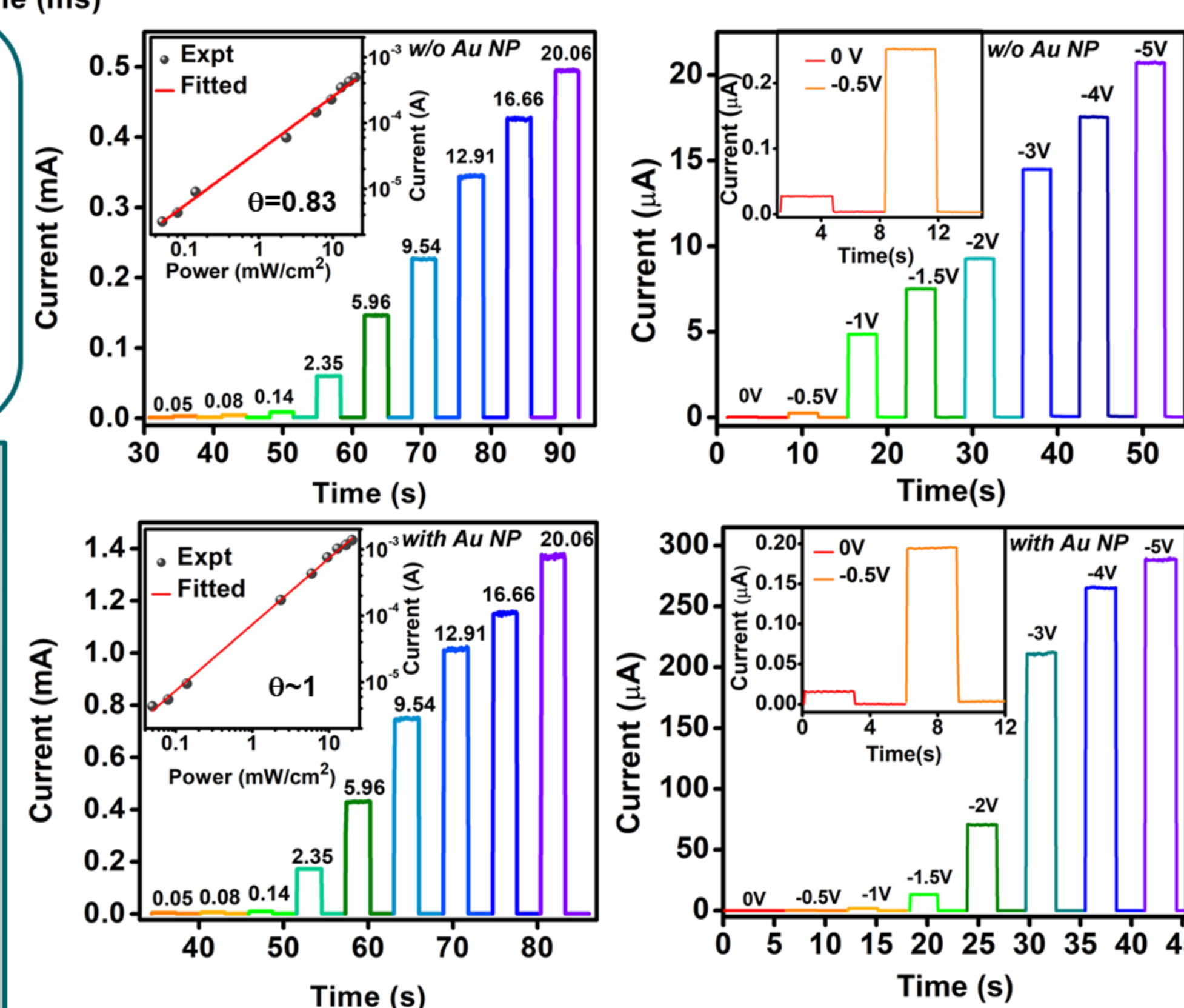


- Asymmetric photo I-V in WS₂/Si shows rectifying behavior, with a high I_{on}/I_{off} ratio ~227.
- Symmetric photo I-V in WS₂/Au/Si indicates Schottky back to back contacts. The I_{on}/I_{off} ratio is ~1.3 × 10⁵.
- High E_a and sporadically scattered Au NPs layer ensures suppressed dark current in WS₂/Au/Si.
- The growth/decay time constants for WS₂/Si ~ 55.1/139.8 μs, whereas, for WS₂/Au/Si, it is ~ 4.4/43.5 μs.



- In WS₂/Si, a type II heterojunction is formed with potential barrier, $\phi_B \sim 0.25$ eV. Upon illumination with 405 nm laser, charge transfer excitons are formed. The excitons dissociate aiding in charge separation.

- For WS₂/Au/Si, at the WS₂/Au interface, a Schottky junction is formed. At the p-Si/Au interface, an Ohmic contact is formed. A built-in potential of 0.5 eV (V₀) develops on the WS₂ side. The electrons from Au overcome the barrier height ($\phi_0 = 1.1$ eV) to transfer to the CB of WS₂ QDs in 2 possible ways: (1) *Hot electrons* in the Au NPs, possessing sufficiently high energy. (2) *Tunneling electrons* that are able to pass through the depletion width, as the WS₂ QDs are monolayered (0.8 nm).
- Electron tunneling is highly elevated in the reverse bias. Also, as the E_F of the WS₂ QDs goes down, there is more effective hot electron transfer.



- Power law ($I = P^\theta$) fitting yields sublinear behaviour ($\theta = 0.83$) indicating presence of trap states in WS₂/Si.
- In WS₂/Au/Si, $\theta \sim 1$. The Au NPs between the WS₂ and the Si allows higher charge separation.
- V dependent photo responses of both PD show operation at 0 bias voltages. At 0 bias, the WS₂/Si has I_{on}/I_{off} of ~8, while WS₂/Au/Si exhibits a high I_{on}/I_{off} of ~280.

CONCLUDING REMARKS

WS₂ QD based vertical hybrid devices can be driven at zero bias. The incorporation of Au NPs serves as a carrier tunneling pathway and the generation of hot electrons for ultra-fast charge transport. The ununiform Au NP arrangement suppresses dark current which further elevates the photodetector performance.

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